



4/20/2008

RELIABILITY MONITOR REPORT
FOR

SVL 0.8 μ m Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX4358ECE+	MAX4845EYT+	MAX7500MSA+	MAX8659ETL+
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The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 55034** **FITS: 2.1**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2007 and 3/31/2008 .

Process Information:

Process Description: SVL 0.8µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	MAX4358ECE+		135C, 5.25V	1000 HRS	47	0	
			135C, 5.25V	1000 HRS	50	0	
			135C, 5.25V	1000 HRS	50	0	
	MAX4845EYT+		135C, 5.25V	1000 HRS	45	0	
	MAX8659ETL+		135C, 5.25V	1000 HRS	44	0	
	MAX7500MSA+		135C, 5.25V	1000 HRS	48	0	
Total:						0	

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